# SN54LVC574A, SN74LVC574A OCTAL EDGE-TRIGGERED D-TYPE FLIP-FLOPS WITH 3-STATE OUTPUTS

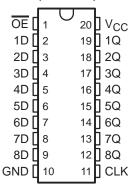
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- EPIC™ (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   < 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Support Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V<sub>CC</sub>)
- Power Off Disables Outputs, Permitting Live Insertion
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and DIPs (J)

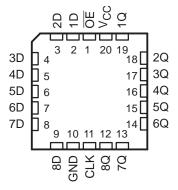
#### description

The SN54LVC574A octal edge-triggered D-type flip-flop is designed for 2.7-V to 3.6-V  $\rm V_{CC}$  operation and the SN74LVC574A octal edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V  $\rm V_{CC}$  operation.

SN54LVC574A . . . J OR W PACKAGE SN74LVC574A . . . DB, DW, OR PW PACKAGE (TOP VIEW)



SN54LVC574A . . . FK PACKAGE (TOP VIEW)



These devices feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels at the data (D) inputs.

A buffered output-enable  $(\overline{OE})$  input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.



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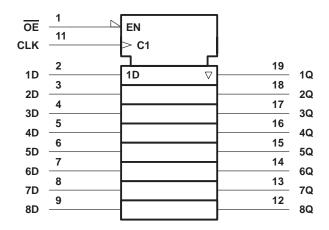
#### description (continued)

The SN54LVC574A is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to  $125^{\circ}$ C. The SN74LVC574A is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

FUNCTION TABLE (each flip-flop)

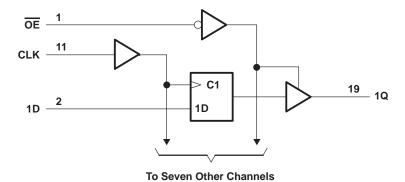
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	$\uparrow$	Н	Н
L	$\uparrow$	L	L
L	L	Χ	$Q_0$
Н	X	Χ	Z

### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)



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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	–0.5 V to 6.5 V
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	$\dots$ -0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Continuous output current, IO	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The value of V<sub>CC</sub> is provided in the recommended operating conditions table.
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions (see Note 4)

			SN54L	VC574A	SN74L	VC574A	LINUT
		ľ	MIN	MAX	MIN	MAX	UNIT
\/	Complete and	Operating	2	3.6	1.65	3.6	V
VCC	Supply voltage	Data retention only	1.5		1.5		V
		V <sub>CC</sub> = 1.65 V to 1.95 V			0.65 × V <sub>CC</sub>		
$V_{IH}$	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$			1.7		V
		V <sub>CC</sub> = 2.7 V to 3.6 V	2		2		
		V <sub>CC</sub> = 1.65 V to 1.95 V				0.35 × V <sub>CC</sub>	
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 2.3 V to 2.7 V				0.7	V
		V <sub>CC</sub> = 2.7 V to 3.6 V		0.8		0.8	
٧ı	Input voltage		0	5.5	0	5.5	V
\/-	0	High or low state	0	Vcc	0	Vcc	V
VO	Output voltage	3 state	0	5.5	0	5.5	V
		V <sub>CC</sub> = 1.65 V				-4	
1	High lovel output ourrent	V <sub>CC</sub> = 2.3 V				-8	mA
ЮН	High-level output current	V <sub>CC</sub> = 2.7 V		-12		-12	mA
		VCC = 3 V	0.8 0 5.5 0 VCC 0 5.5		-24		
		V <sub>CC</sub> = 1.65 V				4	
la.	Love lovel output ourrent	V <sub>CC</sub> = 2.3 V				8	A
lOL	Low-level output current	V <sub>CC</sub> = 2.7 V		12		12	mA
		VCC = 3 V		24		24	
Δt/Δν	Input transition rise or fall rate		0	6	0	6	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS		SN54	1LVC574	A	SN74	LVC574	Α .	UNIT	
PARAMETER	LESI CONDIII	IONS	Vcc	MIN	TYP†	MAX	MIN	TYP <sup>†</sup>	MAX	UNII
	ΙΟΗ = -100 μΑ		1.65 V to 3.6 V				V <sub>CC</sub> -0.2			
	ΙΟΗ = -100 μΑ		2.7 V to 3.6 V	V <sub>CC</sub> -0.2						
	$I_{OH} = -4 \text{ mA}$		1.65 V				1.2			
Voн	$I_{OH} = -8 \text{ mA}$		2.3 V				1.7			V
	I <sub>OH</sub> = -12 mA		2.7 V	2.2			2.2			
	IOH = -12 IIIA		3 V	2.4			2.4			
	$I_{OH} = -24 \text{ mA}$		3 V	2.2			2.2			
	I <sub>OL</sub> = 100 μA		1.65 V to 3.6 V						0.2	
			2.7 V to 3.6 V			0.2				ı
\/o:	I <sub>OL</sub> = 4 mA		1.65 V						0.45	V
VOL	I <sub>OL</sub> = 8 mA		2.3 V						0.7	V
	I <sub>OL</sub> = 12 mA		2.7 V			0.4			0.4	
	I <sub>OL</sub> = 24 mA		3 V			0.55			0.55	
lį	V <sub>I</sub> = 0 to 5.5 V		3.6 V			±5			±5	μΑ
l <sub>off</sub>	$V_I$ or $V_O = 5.5 V$		0						±10	μΑ
loz	$V_0 = 0 \text{ to } 5.5 \text{ V}$		3.6 V			±15			±10	μΑ
	$V_I = V_{CC}$ or GND		0.01/			10			10	
lcc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\ddagger}$	IO = 0	3.6 V			10			10	μΑ
ΔlCC	One input at V <sub>CC</sub> – 0.6 Other inputs at V <sub>CC</sub> or		2.7 V to 3.6 V			500			500	μΑ
C <sub>i</sub>	$V_I = V_{CC}$ or GND		3.3 V		4			4		pF
Co	$V_O = V_{CC}$ or GND		3.3 V		5.5			5.5		pF

<sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. ‡ This applies in the disabled state only.

#### timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

			SN54LVC574A				
		V <sub>CC</sub> = 2.7 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX		
fclock	Clock frequency		150		150	MHz	
t <sub>W</sub>	Pulse duration, CLK high or low	3.3		3.3		ns	
t <sub>su</sub>	Setup time, data before CLK↑	2		2		ns	
t <sub>h</sub>	Hold time, data after CLK↑	2		2		ns	

## timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

		SN74LVC574A								
		V <sub>CC</sub> = ± 0.1	$C = 1.8 \text{ V}$ $V_{CC} = 2.5 \text{ V}$ $\pm 0.2 \text{ V}$ $V_{CC} = 2.7 \text{ V}$		V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT			
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		†		†		150		150	MHz
t <sub>W</sub>	Pulse duration, CLK high or low	†		†		3.3		3.3		ns
t <sub>su</sub>	Setup time, data before CLK↑	†		†		2		2		ns
t <sub>h</sub>	Hold time, data after CLK↑	†		†		1.5		1.5		ns

<sup>†</sup> This information was not available at the time of publication.

### switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> =	2.7 V	V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	
f <sub>max</sub>			150		150		MHz
t <sub>pd</sub>	CLK	Q		8	1	7	ns
t <sub>en</sub>	ŌĒ	Q		9	1	7.5	ns
t <sub>dis</sub>	ŌĒ	Q		7	0.5	6.4	ns

### switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

						SN74L\	/C574A				
PARAMETER	FROM (INPUT)	TO (OUTPUT)		V <sub>CC</sub> = 1.8 V V <sub>CC</sub> = 2.5 V ± 0.15 V ± 0.2 V		2.5 V 2 V	VCC =	2.7 V	V <sub>CC</sub> = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			†		†		150		150		MHz
<sup>t</sup> pd	CLK	Q	†	†	†	†		8	2.2	7	ns
t <sub>en</sub>	ŌĒ	Q	†	†	†	†		8.5	1.5	7.5	ns
<sup>t</sup> dis	ŌE	Q	†	†	†	†		7	1.7	6.4	ns
t <sub>sk(o)</sub> ‡										1	ns

<sup>†</sup> This information was not available at the time of publication.

#### operating characteristics, T<sub>A</sub> = 25°C

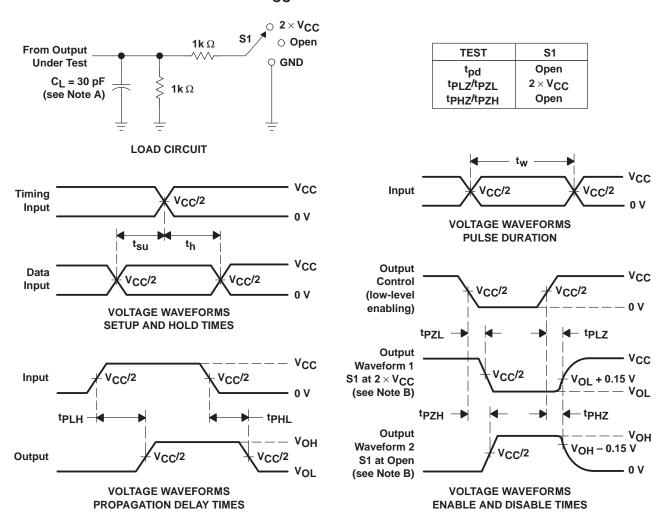
	PARAMETER	TEST CONDITIONS	V <sub>CC</sub> = 1.8 V ± 0.15 V	V <sub>CC</sub> = 2.5 V ± 0.2 V	V <sub>CC</sub> = 3.3 V ± 0.3 V	UNIT		
			CONDITIONS	TYP	TYP	TYP		
C <sub>pd</sub>	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	43	рF	
Ppa	per flip-flop	Outputs disabled	1 = 10 MH2	†	†	15	þг	

<sup>†</sup> This information was not available at the time of publication.



<sup>‡</sup> Skew between any two outputs of the same package switching in the same direction

### PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$



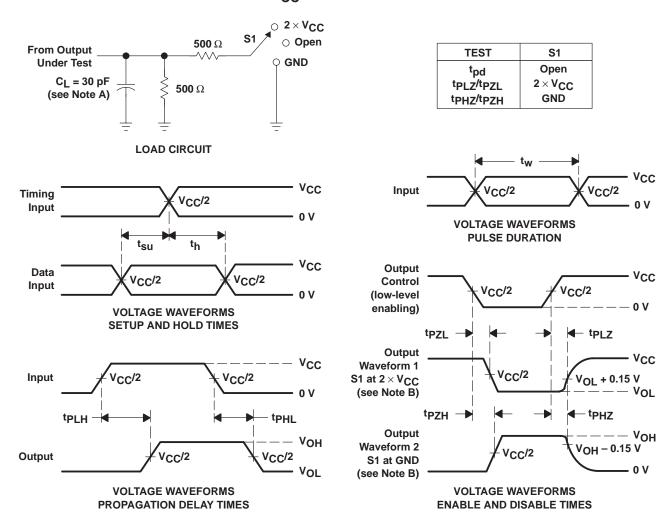
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq 2$  ns.  $t_f \leq 2$  ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzl and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



### PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$

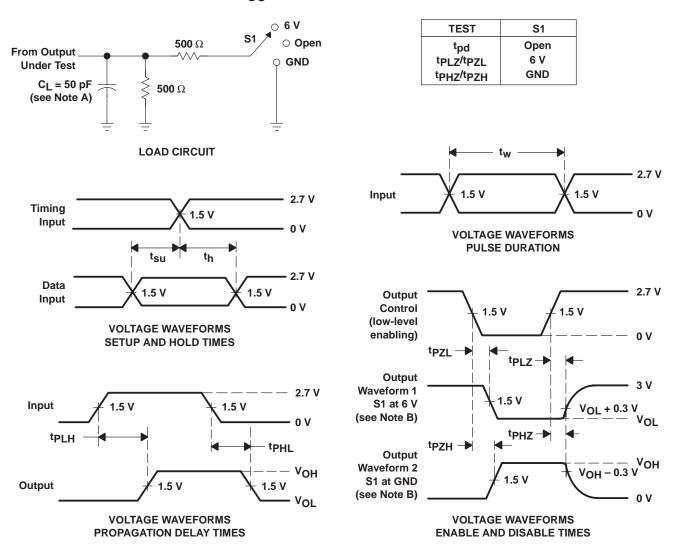


NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_0 = 50 \Omega$ ,  $t_f \leq 2$  ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

### PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.7 V AND 3.3 V $\pm$ 0.3 V



- NOTES: A. C<sub>I</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \Omega$ ,  $t_f \leq 2.5 \text{ ns.}$
  - D. The outputs are measured one at a time with one transition per measurement.
  - E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
  - F. tpzL and tpzH are the same as ten.
  - G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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